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"FAST DECODING TECHNIQUES FOR EXTENDED
SINGLE-AND-DOUBLE-ERROR-CORRECTING REED SOLOMON CODES"

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SUMMARY

A problem in designing semiconductor memories is to provide some measure of error control without requiring excessive coding overhead or decoding time. For example, some 256K-bit dynamic random access memories are organized as 32K x 8 bit-bytes. Byte-oriented codes such as Reed Solomon (RS) codes [1] can provide efficient low overhead error control for such memories. However, the standard iterative algorithm [2] for decoding RS codes is too slow for these applications.

In this paper we investigate some special high speed decoding techniques for extended single-and-double-error-correcting RS codes. These techniques are designed to find the error locations and the error values directly from the syndrome without having to form the error locator polynomial and solve for its roots. Two codes are considered:

I. A \( d_{min} = 4 \) SEC-DED Code

A \((2^m + 2, 2^m - 1)\) code is formed by adding a 3 x 3 identity matrix to the parity-check matrix of the RS code with generator polynomial

\[ g(x) = (x + 1)(x + a)(x + a^2), \]

where \( a \) is a primitive element of \( GF(2^m) \). It is shown that this extended code with three additional information symbols has minimum distance \( d_{min} = 4 \), and hence is capable of single-error-correction (SEC) and double-error-detection (DED).

Decoding of the error vector \( e \) is based directly on the syndrome

\[ s = e H^T = (s_0, s_1, s_2), \]

where \( H \) is the parity-check matrix of the extended code. The decoding method can be summarized as follows:

1) A single error in the first three positions (corresponding to the identity positions of \( H \)) results in a syndrome with only one nonzero element.

2) If a single error occurs in any other position, the syndrome elements satisfy

\[ a^{i-3} = \frac{s_1}{s_0} = \frac{s_2}{s_1}, \]

and \( i \) gives the error location.

3) If a single syndrome element is zero, or if

\[ \frac{s_1}{s_0} \neq \frac{s_2}{s_1}, \]

a double-byte-error is detected.

In cases 1) and 2), the error value is easily determined from the syndrome.
II. A $d_{\text{min}} = 6$ DEC - TED Code

A $d_{\text{min}} = 6$ RS code is formed from the generator polynomial

$$g(x) = \frac{1}{2} (x + a^i),$$

where $a$ is a primitive element of $\text{GF}(2^m)$. This code is capable of double-error-correction (DEC) and triple-error-detection (TED), and can be extended by adding two additional information symbols (see [1]).

The syndrome $s = e^H = (s_{-2}, s_{-1}, s_0, s_1, s_2)$. Decoding can be summarized as follows:

1) Calculate the following quantities:

$$Y_1 = s_1 s_{-2} + s_{-1} s_0$$
$$Y_2 = s_2 s_{-2} + s_0$$
$$Y_3 = s_0 s_1 + s_1 s_{-1}$$

If $Y_1 = Y_2 = Y_3 = 0$, a single-byte-error occurred with value $s_0$ and location $i$, where $a^i = \frac{s_1}{s_0}$.

2) If $Y_1 \neq 0, Y_2 \neq 0$, and $Y_3 \neq 0$, compute $k = \frac{c}{b^2}$ and $T_2(k)$, where $b \triangleq \frac{Y_2}{Y_1}$, $c \triangleq \frac{Y_3}{Y_1}$, and for a field element $\beta$,

$$T_2(\beta) \triangleq \sum_{i=0}^{m-1} \beta^2^i$$

is the trace of $\beta$. If $T_2(k) = 0$, solve the equation

$$y^2 + by + c = 0$$

using the high-speed method described in [3] to find the error locators $a^i$ and $a^j$ of a double-byte-error.
3) If $T_2(k) = 1$, or if at least one but not all of $\gamma_1$, $\gamma_2$, and $\gamma_3$ equals zero, or if more than two elements of $s$ equal zero, a triple-byte-error is detected.

In case 2), the error values can be found directly from the syndrome and the quantities calculated.

REFERENCES

